

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/593,340	<b>Applicant(s)/Patent under Reexamination</b> INOUE ET AL.
<b>Examiner</b> Chris H. Chu	<b>Art Unit</b> 2874	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
USPTO EAST: USPAT AND USPG-PUB (see attached text)		12/21/2007	CC

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
applicant's cited references	12/21/2007	CC
text search	12/21/2007	CC
class 385 further limiting with text	12/21/2007	CC
IEEE database	12/21/2007	CC